

Notice of References Cited

Application/Control No.

10/543,172

Applicant(s)/Patent Under
Reexamination
KII ET AL.

Examiner

Bai D. Vu

Art Unit

2165

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0035599 A1	03-2002	Matsumoto et al.	709/203
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NON-PATENT DOCUMENTS

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